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|-----------------------------------|--|-------------------------|--|-----------------------------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination 10/719,319 CHEN ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 Patricia L. Hailey |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,548,447 | 04-2003 | Yokoyama et al. | 502/331 |
| * | B | US-2004/0068148 | 04-2004 | Allison et al. | 585/016 |
| * | C | US-6,365,543 | 04-2002 | Schmidt et al. | 502/325 |
| * | D | US-2003/0208095 | 11-2003 | Budin et al. | 585/658 |
| * | E | US-6,846,773 | 01-2005 | Yokoyama et al. | 502/339 |
| * | F | US-6,417,376 | 07-2002 | Yeh et al. | 549/248 |
| * | G | US-6,500,781 | 12-2002 | Luo et al. | 502/326 |
| * | H | US-5,028,577 | 07-1991 | Michaels et al. | 502/243 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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